Certifiable Deep Importance Sampling for Rare-Event Simulation of Black-Box Safety-Critical Systems

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Unsafe deployment of AI-driven physical systems can lead to catastrophic events

Tesla Autopilot Crash, May 2016

Uber Self-Drive Crash, March 2018

Tesla Autopilot Crash, March 2018

Tesla Autopilot Crash, March 2019

Testing autonomous vehicles (AVs) is challenging because:

- Test matrix approaches cannot screen out AVs that excel in the test but not other safety-critical situations (Peng & LeBlanc '12)
- Naturalistic testing takes insurmountable time (Zhao et al. '15)

(NHTSA 2013) In US in 2013,

- Impractical to deploy "test" AVs to observe enough crashes
- Approach: Integrate AV algorithms into high-fidelity simulated naturalistic driving environment (built from historical data)
- Rare-event simulation technique to enhance crash observations in simulation (Zhao et al. 2015, Zhao et al. 2017, Huang et al. 2017, Huang et al. 2018, O'Kelly et al. 2018).

• **Task**: estimate safety measures (e.g. crash probability) of the tested vehicle under specific traffic scenario

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 $P((AV algorithm, environment) \in conflict set)$

d. detailed safety-critical event simulator

Problem Setting

- A stochastic environment denoted $X \sim p$
- Goal: Estimate $\mu = P(X \in S)$ for a rare-event set S
- Rarity parameter γ , so $S = S_{\gamma}$ such that $\mu \to 0$ as $\gamma \to \infty$ E.g., $S_{\gamma} = \{x \in R^d : f(x) \ge \gamma\}$
- Key Challenge: Complicated or "black-box" S

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- Proposals?
	- Mathematical analysis
	- "Black-box" methods such as cross-entropy (De Boer '05, Rubinstein & Kroese '13…), multi-level splitting / subset simulation (Au & Beck '01, Dean & Dupuis '09, Villen-Altamirano '94…)

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	- "Deep Probabilistic Accelerated Evaluation" (Deep-PrAE) (Arief et al. '21)

• To estimate a small probability μ using Monte Carlo estimator $\hat{\mu}_n$, we need a relative accuracy

$$
P(|\hat{\mu}_n - \mu| > \epsilon \mu) \le \delta
$$

for some $0 < \delta, \epsilon < 1$

• Say
$$
\hat{\mu}_n = \frac{1}{n} \sum_{i=1}^n Z_i
$$
 where Z_i i.i.d., unbiased

• Markov inequality:

$$
\frac{Var(Z_i)}{n\epsilon^2\mu^2} \le \delta
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Small RE \Rightarrow Small required n

• Suppose we use naïve Monte Carlo (NMC):

$$
\hat{\mu}_n = \frac{1}{n} \sum_{i=1}^n I(X_i \in S)
$$

• Then
$$
RE = \frac{\mu(1-\mu)}{\mu^2} = \frac{1}{\mu} \implies n \approx \frac{1}{\mu}
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 blows up when $\mu \to 0$

• If $\mu \approx e^{-c\gamma}$, then $n \approx e^{c\gamma}$ Exponential growth in γ

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• If $\mu \approx e^{-c\gamma}$, then $n \approx e^{c\gamma}$ Exponential growth in γ Efficiency certificate: required *n* or RE \approx log(1 μ)

Importance sampling (IS):

We generate X from a new IS distribution \tilde{p} , and output $Z = I(X \in S)L(X)$ where $L(X) =$ $\left\langle dp\right\rangle$ $d\widetilde{p}$ (X) is the likelihood ratio

Estimator $\hat{\mu}_n =$ 1 $\frac{1}{n}\sum_{i=1}^n Z_i$ is unbiased

How do we obtain a Z that has an efficiency certificate?

- Say $X \sim N(\lambda, \Sigma)$
- Estimate $P(X \in S)$
- \bullet Look for highest-density point inside S: $a^* = argmin_{x \in S}$ 1 2 $(x - \lambda)^T \Sigma^{-1} (x - \lambda)$

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Not always good..

How do we obtain a Z that has an efficiency certificate?

Dominant set = ${a_j:}$ any point in S is on the "far-side" half-space of at least one a_j }

 a_1

 a_2

 \mathcal{S}_{0}

How do we obtain a Z that has an efficiency certificate?

An efficient IS needs to "take care" of all dominant points, by using a mixture distribution:

$$
\tilde{p} = \sum_j q_j N(a_j, \Sigma)
$$

References: Sadowsky & Bucklew 1990, Asmussen & Glynn 2007, Blanchet & L. 2012, Juneja & Shahabuddin 2006, Rubino & Tuffin 2009, Owen '13, L'Ecuyer et al. 2009, Honnappa et al. 2018, Nakayama 2012, Botev et al. 2007, Rubinstein & Kroese 2016, Rhee et al. 2019…

- 1) The relative error of $\hat{\mu}_n$ grows exponentially in γ .
- 2) If *n* is polynomial in γ , we have $P(|\hat{\mu}_n \overline{\Phi}(\gamma)| > \varepsilon \overline{\Phi}(\gamma)) = O(\frac{\gamma}{n \varepsilon})$ $\frac{r}{n\varepsilon^2}$ for any $\varepsilon > 0$ where $\overline{\Phi}(\gamma) = P(X \ge \gamma) < \mu$, and the empirical relative error = $O(n^2)$ with probability higher than $1 - 1/2^n$.

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- 2) But you don't know..
- In experiments, you see a nice empirical RE that gives you high "confidence" on your result, but in fact you run into systematic underestimation

Cross-entropy method:

- Choose a parametric IS class \tilde{p}
- Empirically minimize Kullback-Leibler divergence between \tilde{p} and a "zerovariance" distribution

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Cross-entropy method:

- Choose a parametric IS class \tilde{p}
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May not converge to an IS that has efficiency certificate.. Hence possibly under-estimate, but you don't know..

• Relaxed Efficiency Certificate: Relax the rare-event estimation problem to estimating upper and lower bounds

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- A two-stage procedure:
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	- Stage 2: Search dominant points of the learned set and run mixture IS

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	- Stage 1: Rare-event-set learning
	- Stage 2: Search dominant points of the learned set and run mixture IS
- A suitably constructed ReLU neural network classifier to learn set (Stage 1) achieves the relaxed efficiency certificate

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with sample size
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Want to get a good upper bound for μ with $n \approx \log(\frac{1}{\mu})$ μ Analogously for lower bound

We achieve a relative accuracy

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with sample size $n \approx \log\left(\frac{1}{n}\right)$ μ

A sufficient condition:

- $\hat{\mu}_n$ is upward biased, i.e., $\bar{\mu} = E \hat{\mu}_n \ge \mu$, and
- $\hat{\mu}_n$ has efficiency certificate to estimate $\bar{\mu}$

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- $\hat{\mu}_n$ is upward biased, i.e., $\bar{\mu} = E \hat{\mu}_n \ge \mu$, and
- $\hat{\mu}_n$ has efficiency certificate to estimate $\bar{\mu}$ \leftarrow Use mixture IS, if we know

the rare-event set

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If we can learn \overline{S} such that $\overline{S} \supset S$, then $\overline{\mu} = P(X \in \overline{S}) \ge P(X \in S) = \mu$

Goal: Obtain a good outer approximation of S

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Goal: Obtain a good outer approximation of S

How to learn a set?

Classification task:

- Sample \tilde{X}_i and label $Y_i = I(\tilde{X}_i \in S)$
- Then "train" a classifier using the data (\tilde{X}_i, Y_i)

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Outer approximation means that the false negative rate is zero…

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Orthogonal monotone set: If $x \in S$, then any $x' \geq x$ also $\in S$

An easy outer approximation is to take the complement of the "step- \hat{x} " boundary" formed by all 0-labeled ${\tilde X}_i$

Lazy-learner IS: Simulate the probability of falling into this "step-boundary" set

Deep-learning-based IS:

Train a ReLU-activated classifier to obtain an outer approximation of \overline{S}

First train $\{\widehat{g}(x) \geq \kappa\}$, then tune κ to satisfy $\overline{S} \supset S$

Stage 2: Learn the dominant points and construct mixture IS

Deep-PrAE IS:

Right # of dominant points, and satisfy relaxed efficiency certificate

Behind-the-Scene 1: MIP to Search "Best" Dominant Points in ReLU Network

ReLU network:

- **I** Input S_0 .
- In layer k with input s_k , $y_k = W_k s_k + b_k$, $s_{k+1} = \sigma(y_k) = \max\{y_k, 0\}.$

$$
\min_{x,s_0,...,s_L,z_1,...,z_L} ||x||^2
$$
\n*g(x) \ge \gamma*\n*s.t.*\n
$$
s_L \ge \gamma
$$
\n*s.t.*\n
$$
s_L \ge \gamma
$$
\n*s.t.*\n
$$
s_i \ge W_i^T s_{i-1} + b_i - l(1-z_i), \quad i = 1,...,L
$$
\n*x*: input variables\n*s_i*'s: input/output in each layer\n*z_i*'s: integer variables\n*s_i \ge 0, i = 1,...,L*\n*z_i \in \{0,1\}^{n_i}, \quad i = 1,...,L*\n*z_i \in \{0,1\}^{n_i}, \quad i = 1,...,L*\n*s_0 = x*\n*s_i = max\{W_i^T s_{i-1} + b_i, 0\}*

- The number of integer variables is the number of neurons.
- Each neuron has four corresponding constraints.

Behind-the-Scene 2: Sequential "Cutting Plane" to Search All Dominant Points in ReLU Network

Input: Prediction model $g(x)$, threshold γ . **Output:** Dominating-points set A. 1 Start with $A = \emptyset$; 2 While $\{x: g(x) \geq \gamma, a'_i(x-a_i) < 0, \ \forall a_i \in A\} \neq \emptyset$ do Find a dominating point a by solving the optimization problem $\overline{\mathbf{3}}$ $a = \arg\min_{x} \|x\|^2$ s.t. $g(x) \geq \gamma$ $a'_i(x-a_i) < 0$, for $\forall a_i \in A$ and update $A \leftarrow A \cup \{a\};$ 4 End

Behind-the-Scene 3: Conservativeness of Upper Bounds

With probability at least $1 - \delta$,

$$
P(false + ve) \leq \frac{R(g^*) + 2 \sup_{g \in \mathcal{G}} |R_{n_1}(g) - R(g)|}{h(\kappa^* - t(\delta, n_1) \sqrt{d} \text{Lip}(g^*) - ||\hat{g} - g^*||_{\infty})}.
$$

Here, Lip(g^*) is the Lipschitz parameter of g^* , and $t(\delta, n_1) =$ 3 $\log (n_1 q_l) + \text{dlog } M + \log^{\textstyle \frac{1}{\delta}}$ n_1q_l 1 δ .

Example

- CE GMM-2 captures enough dominant $points \Rightarrow efficient$ and gives accurate estimate
- CE Naive is "confident" but underestimate
- Deep-PrAE (modified) locates enough dominant points \Rightarrow efficient and gives accurate estimate

Example of Intelligent Driver Model (IDM)

- A car-following scenario involving a human-driven lead vehicle followed by an autonomous vehicle
- Time horizon $T = 60s$ with a sequence of 15 Gaussian random actions at a 4 second epoch
- 10,000 sample budget.

Self-Driving Example

- Deep-PrAE produces tighter bounds than LL
- When $y = 1$, LL UB has 5,644 dominant points vs 42 in Deep-PrAE
- Most methods are "confident" about their estimation, and some of them must under-estimate

Summary

- Motivated by safety-testing of intelligent physical systems
- Motivated from the perils of black-box variance reduction algorithms
- Deep Probabilistic Accelerated Evaluation (Deep-PrAE): Combine ReLU-activated neural net classifiers for set learning with dominant point methodology to design IS with relaxed efficiency certificate

+ve Thoughts:

- Towards "model-free" importance sampling
- Towards "high-dimensional" importance sampling

-ve Thoughts:

- Tail model error
- How to interpret rare-event probability

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